

General Description

- Proprietary α MOS5™ technology
- Low $R_{DS(ON)}$
- Optimized switching parameters for better EMI performance
- Enhanced body diode for robustness and fast reverse recovery

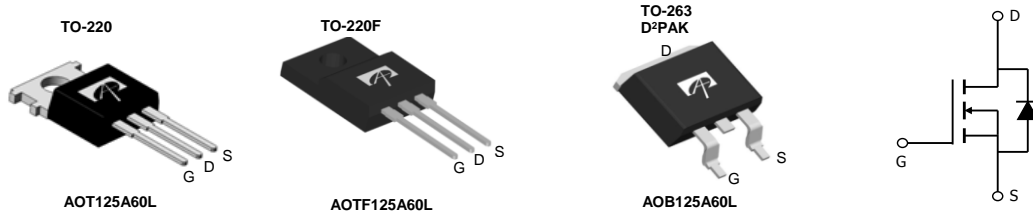
Applications

- SMPS with PFC, Flyback and LLC topologies
- Micro inverter with DC/AC inverter topology

Product Summary

$V_{DS} @ T_{j,max}$	700V
I_{DM}	100A
$R_{DS(ON),max}$	< 0.125 Ω
$Q_{g,typ}$	39nC
$E_{OSS} @ 400V$	6.3 μ J

100% UIS Tested
 100% R_g Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOTF125A60L	TO220F	Tube	1000
AOT125A60L	TO220	Tube	1000
AOB125A60L	TO263	Tape&Reel	800

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOT(B)125A60L	AOTF125A60L	Units
Drain-Source Voltage	V_{DS}	600		V
Gate-Source Voltage	V_{GS}	± 20		V
Continuous Drain Current	I_D	$T_C=25^\circ\text{C}$	28	28*
		$T_C=100^\circ\text{C}$	18	18*
Pulsed Drain Current ^C	I_{DM}	100		A
Avalanche Current ^C $L=1\text{mH}$	I_{AR}	7.9		A
Repetitive avalanche energy ^C	E_{AR}	31		mJ
Single pulsed avalanche energy ^G	E_{AS}	555		mJ
MOSFET dv/dt ruggedness	dv/dt	100		V/ns
Diode reverse recovery $V_{DS}=0$ to 400V, $I_F \leq 20\text{A}$, $T_J=25^\circ\text{C}$	dv/dt	20		V/ns
	di/dt	500		A/us
Power Dissipation ^B	P_D	$T_C=25^\circ\text{C}$	357	36
		Derate above 25 $^\circ\text{C}$	2.9	0.3
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		$^\circ\text{C}$
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	T_L	300		$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	AOT(B)125A60L	AOTF125A60L	Units
Maximum Junction-to-Ambient ^{A,D}	$R_{\theta JA}$	65	65	$^\circ\text{C}/\text{W}$
Maximum Case-to-sink ^A	$R_{\theta CS}$	0.5	---	$^\circ\text{C}/\text{W}$
Maximum Junction-to-Case	$R_{\theta JC}$	0.35	3.4	$^\circ\text{C}/\text{W}$

* Drain current limited by maximum junction temperature.

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V, T _J =25°C	600			V
		I _D =250μA, V _{GS} =0V, T _J =150°C		700		
BV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, V _{GS} =0V		0.51		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =600V, V _{GS} =0V			1	μA
		V _{DS} =480V, T _J =125°C			10	
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =5V, I _D =250μA	3.3	3.9	4.5	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =14A		0.108	0.125	Ω
g _{FS}	Forward Transconductance	V _{DS} =10V, I _D =14A		21		S
V _{SD}	Diode Forward Voltage	I _S =14A, V _{GS} =0V		0.86	1.2	V
I _S	Maximum Body-Diode Continuous Current				28	A
I _{SM}	Maximum Body-Diode Pulsed Current ^C				100	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz		2993		pF
C _{oss}	Output Capacitance			85		pF
C _{o(er)}	Effective output capacitance, energy related ^H	V _{GS} =0V, V _{DS} =0 to 480V, f=1MHz		73		pF
C _{o(tr)}	Effective output capacitance, time related ^I			305		pF
C _{rss}	Reverse Transfer Capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz		0.8		pF
R _g	Gate resistance	f=1MHz		2.3		Ω
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =480V, I _D =14A		39		nC
Q _{gs}	Gate Source Charge			19		nC
Q _{gd}	Gate Drain Charge			9		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =400V, I _D =14A, R _G =5Ω		39		ns
t _r	Turn-On Rise Time			34		ns
t _{D(off)}	Turn-Off DelayTime			56		ns
t _f	Turn-Off Fall Time			19		ns
t _{rr}	Body Diode Reverse Recovery Time			375		ns
I _{rm}	Peak Reverse Recovery Current	I _F =14A, di/dt=100A/μs, V _{DS} =400V		34		A
Q _{rr}	Body Diode Reverse Recovery Charge			8		μC

A. The value of R_{θJA} is measured with the device in a still air environment with T_A=25° C.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.

G. L=60mH, I_{AS}=4.3A, R_G=25Ω, Starting T_J=25° C.

H. C_{o(er)} is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{(BR)DSS}.

I. C_{o(tr)} is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{(BR)DSS}.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

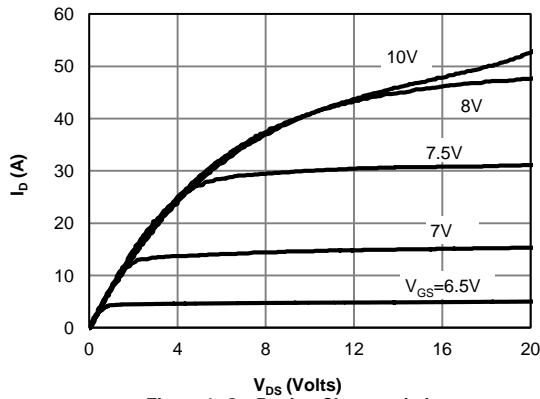


Figure 1: On-Region Characteristics

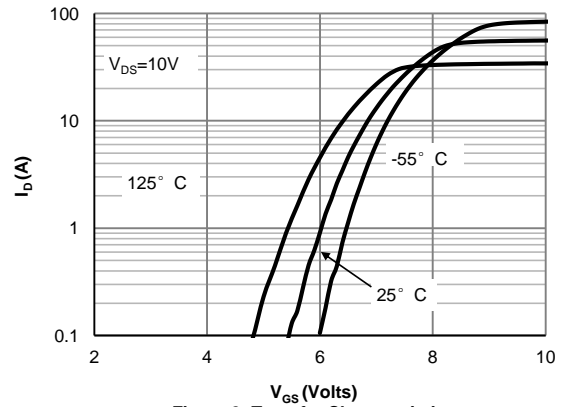


Figure 2: Transfer Characteristics

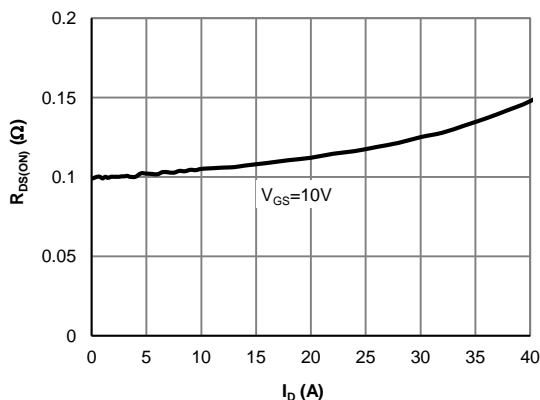


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

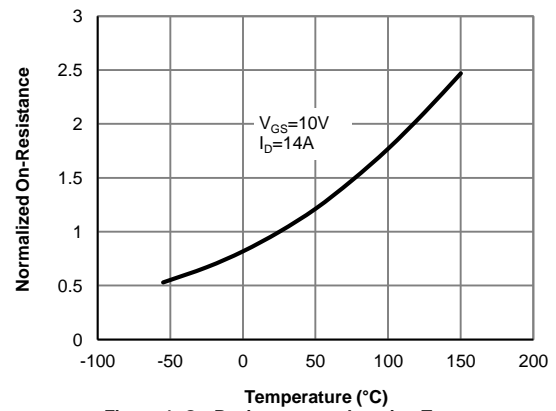


Figure 4: On-Resistance vs. Junction Temperature

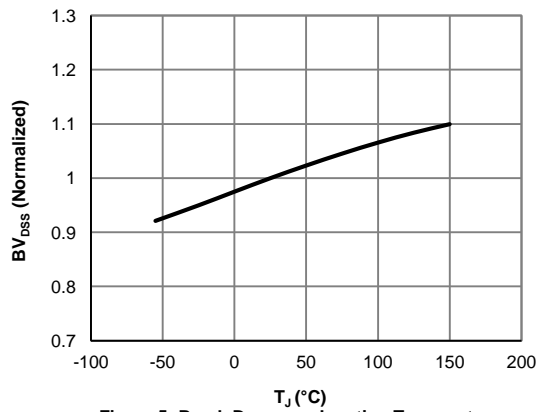


Figure 5: Break Down vs. Junction Temperature

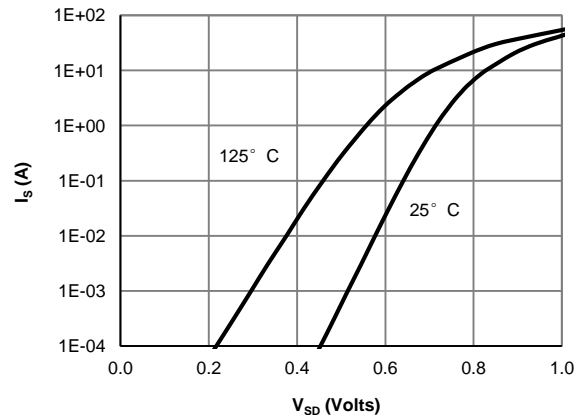


Figure 6: Body-Diode Characteristics

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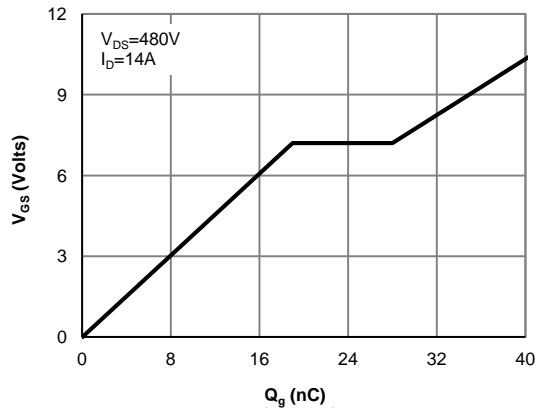


Figure 7: Gate-Charge Characteristics

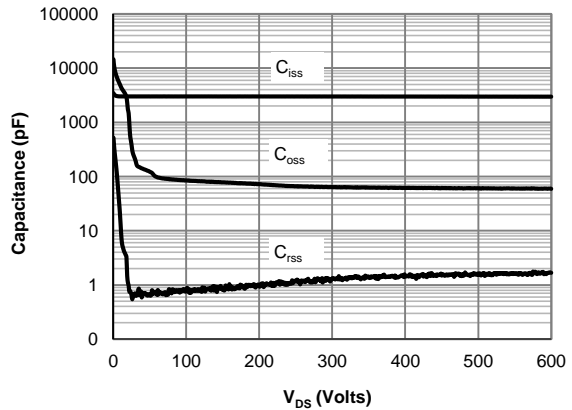


Figure 8: Capacitance Characteristics

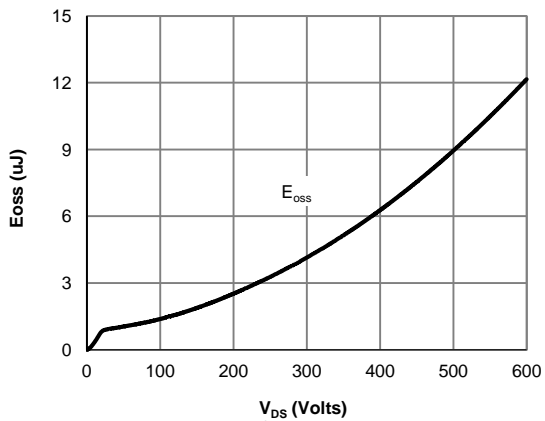


Figure 9: Coss stored Energy

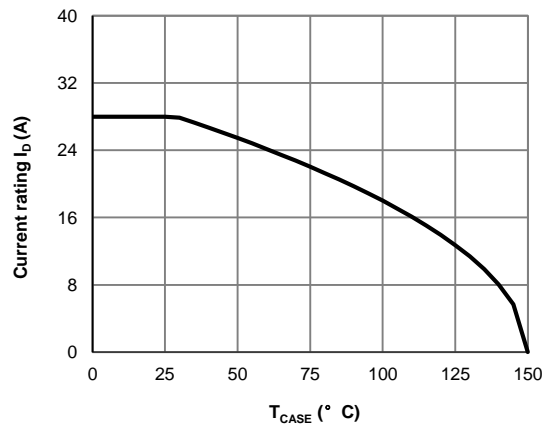


Figure 10: Current De-rating (Note F)

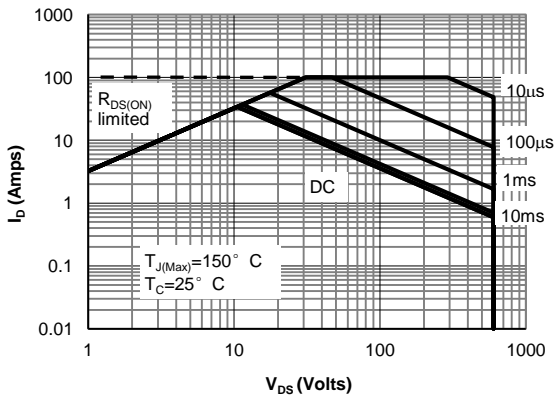


Figure 11: Maximum Forward Biased Safe Operating Area for AOT(B)125A60L (Note F)

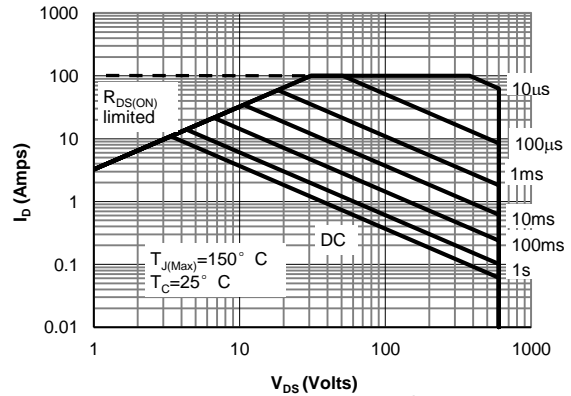


Figure 12: Maximum Forward Biased Safe Operating Area for AOTF125A60L (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

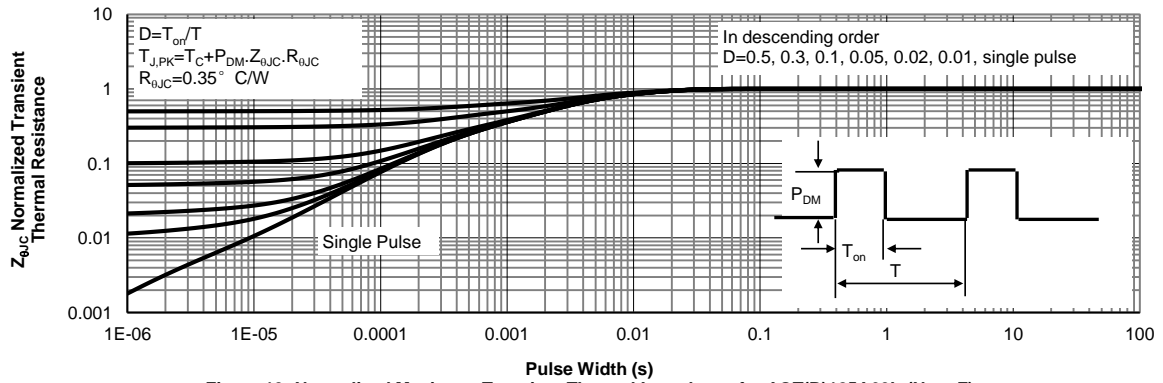


Figure 13: Normalized Maximum Transient Thermal Impedance for AOT(B)125A60L (Note F)

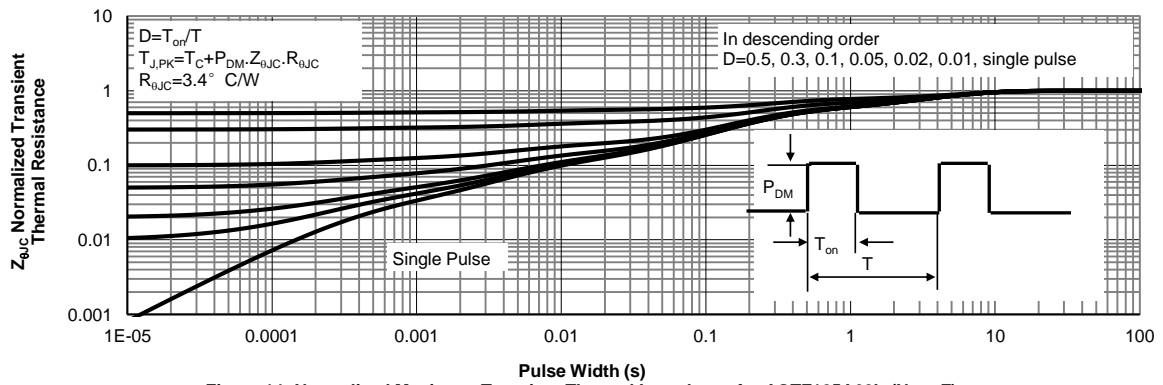
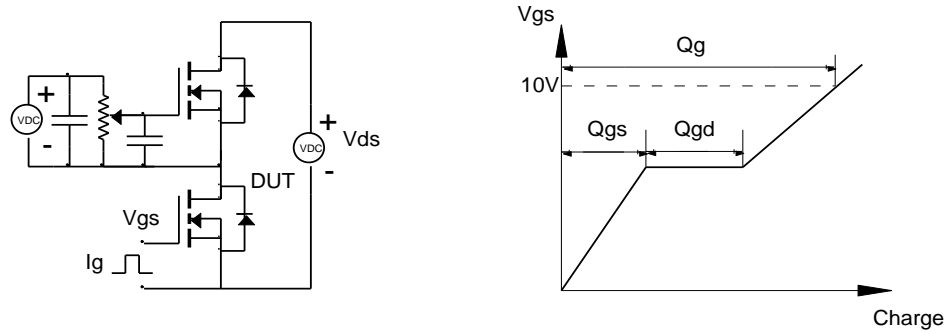
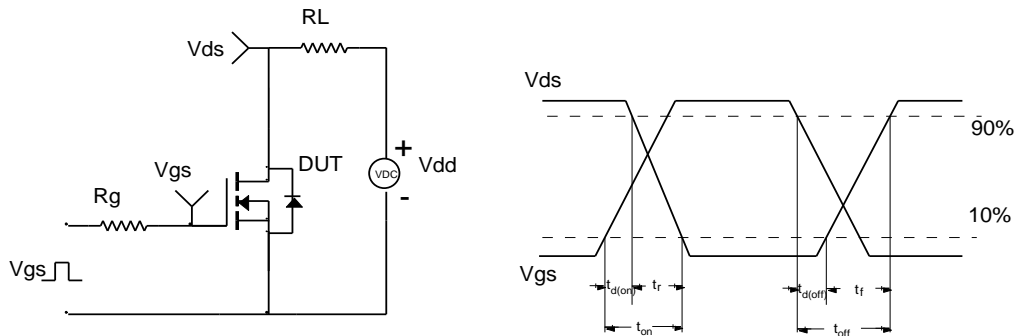


Figure 14: Normalized Maximum Transient Thermal Impedance for AOTF125A60L (Note F)

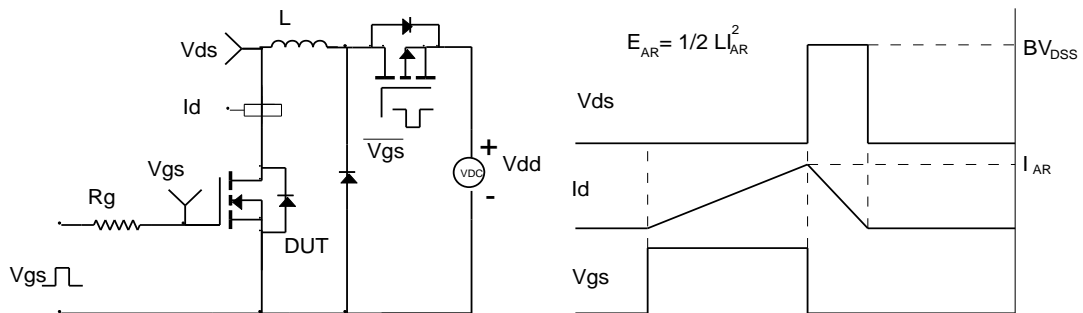
Gate Charge Test Circuit & Waveform



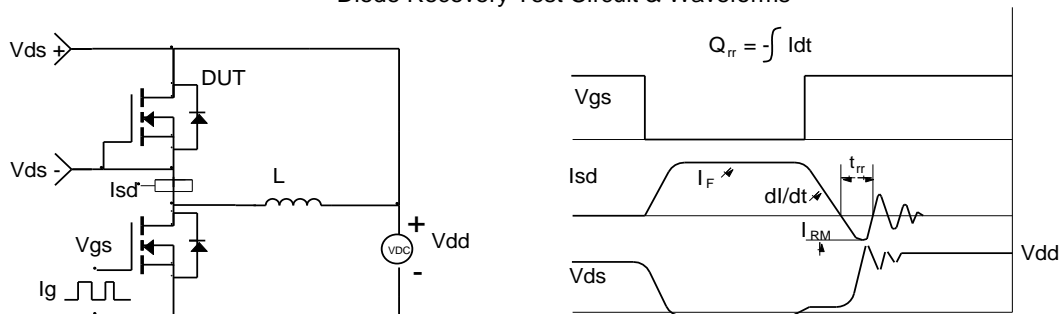
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



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